

**Search Notes**

Application/Control No.

10/767,312

Examiner

David E. Bochna

Applicant(s)/Patent under  
Reexamination

JEWETT ET AL.

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner
285	141.1	7/21/2005	DB
	139.1		
	139.2		
	139.3		
	204		
	207		
	364		
	353		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner